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ToF-SIMS spectral analysis of pristine and neutron irradiated single crystal tungsten

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ABSTRACT

Dataset link: Tungsten Data (Original data)

Keywords: Time-of-flight secondary ion mass spectrometry Single crystal tungsten Neutron irradiation Transmutation Isotopic composition Time-of-flight secondary ion mass spectrometry (ToF-SIMS) has many promising features in studying materials including high spatial resolution and high mass accuracy of elements, molecules, and isotopes. Its ability to resolve isotopes is especially attractive in studying transmutation products of single crystal tungsten (SCW) post neutron irradiation. Tungsten (W) is a contender of plasma facing materials (PFMs) due to its high thermal and radiological stability. PFMs to be used in the construction of fusion vessels are subject to high temperature and neutron irradiation, resulting in changes to materials including transmutation, which ultimately impact material mechanical and thermal properties. We used IONTOF TOF.SIMS V instrument equipped with a 30 keV Bi⁴₃ primary ion beam to study pristine SCW and irradiated SCW speciemens. Scanning electron microscope coupled with focused ion beam (SEM-FIB) was used to reduce the dosage of neutron irradiated tungsten and prepare for specimens for SIMS analysis. Static ToF-SIMS spectra were obtained, and transmutation product peak identification was presented in this work. Identified molecules and molecular fragments were compared against isotope theoretical mass to charge ratios of tungsten, rhenium, osmium, and other relevant products. Our results show that ToF-SIMS provides a viable means to study transmutation products of W post neutron irradiation. Such applications are suitable to investigate transmutation effects on materials that are being considered and developed for fusion pilot plants.

Specifications Table

			The raster size for the pristine single crystal tungsten
Subject	6. Surface and interface modification by directed energy		region of interest was $150 \times 150 \ \mu m^2$. The raster size for
	deposition		the irraidated single crystal tungsten region of interest
Specific subject area	Single crystal tungsten surface analysis		was $100 \times 100 \ \mu\text{m}^2$. The number of scans per depth
Type of data	Table		profile scans were 450 for unirradiated SCW and 602 for
	Figure		irradiated W18. Peak identifications are based on mass
How data were	Mass spectrometry		formula with a mass deviation of less than 65 ppm.
acquired	Instruments: Time-of-flight secondary ion Mass	Data source location	Institution: Oak Ridge National Laboratory
	spectrometry		City/Town/Region: Oak Ridge, TN
	Make and model and of the instruments used: IONTOF		Country: United States of America
	TOF.SIMS V	Data accessibility	Available via Dr. Xiao-Ying Yu's GitHub site, git@code.
Data format	Raw		ornl.gov:nsrd_au/data_pub_sharing.githttps://github.
	Analyzed		com/Gparke4/Data-ToF-SIMS-spectral-analysis-of-pristi
Parameters for data	Compilation of scans with 30 keV Bi ₃ ⁺ metal ion gun		ne-and-neutron-irradiated-single-crystal-tungsten
collection	rastered over the field of view of $150 imes 150 \ \mu m^2$ area.	Related research	None
Description of data	Static ToF-SIMS spectra were obtained using an IONTOF	article	
collection	TOF.SIMS V equipped with a 30 keV Bi_3^+ metal ion gun.		
	(continued on next column)		

(continued)

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1. Value of the data

- Tungsten (W) and its alloys have attracted interest as the leading potential plasma facing material (PFM) candidate due to its ability to endure extreme conditions of exposure of severe thermal loads, high-neutron-energy bombardments, and neutron fluences in a fusion power plant [1–3]. Neutron exposure induces transmutation of W and related structural changes and consequently mechanical property degradation like hardening and brittleness. Reported transmutation products for pure W include rhenium (Re), tantalum (Ta), osmium (Os), and hafnium (Hf).
- Transmutation is known to affect W and alloys, available mass spectrometry data that characterize such isotopes are scarce. Bulk mass spectrometry, such as inductively coupled plasma mass spectrometry or thermal ionization mass spectrometry, does not have sufficient mass resolving power to identify products such as ¹⁸²W, ¹⁸³W, and transmutation products such as Re or Os as well as their isotopes that are close in mass.
- Time-of-flight secondary ion mass spectrometry (ToF-SIMS) offers high mass resolution, mass accuracy, and spatial resolution for metal



Fig. 1. ToF-SIMS spectral plot of the unirradiated single crystal tungsten specimen, SCW, in the m/z^+ range of 0–800 in the positive ion mode. Spectral results were reconstructed from scans 47 to 450 to reduce possible surface oxidation and contamination.

and alloy studies [4,5]. It offers superior detection selectivity and sensitivity of elemental and isotopic analysis in metals. We study and compare the ToF-SIMS spectral analysis of the pristine and neutron irradiated single-crystal tungsten (SCW) specimens in this work. The tungsten coupons were irradiated in the High Flux Isotope Reactor (HFIR) facility as part of the fusion materials research at ORNL.

• This data set provides the first observations of irradiated SCW in comparison with pristine unirradiated SCW. The irradiated SCW post neutron irradiation shows a significant amount of transmutation products from the SEM-FIB liftout. We provide the first data set that can be used as reference data of SCW to support the development of PFM for the fusion materials research community.

2. Data Description

We focus on reporting the elemental and isotopic composition of relevance to SCW and its transmutation products after irradiation. Collected ToF-SIMS spectra have the mass range of 0–800 Da. We highlighted the mass range of 150–225 Da, because this region is of interest for W and its transmutation products, such as Re and Os. Fig. 1 shows the ToF-SIMS spectra of unirradiated SCW in the positive mode. Similarly, Fig. 2 shows the spectra of the un-shielded, irradiated SCW, designated as W18, in the positive mode. Figs. 3 and 4 depict the sectional SIMS spectra of the pristine and irradiated SCW coupons, respectively, showing a closer look of the isotopes of W and W clusters for SCW as well as transmutation products and corresponding isotopes in the same mass regions.

Table 1 shows possible peak identifications of pure SCW, designated as SCW, in the positive mode. The unirradiated SCW spectra showed observation of pristine tungsten signals and the accompanying clusters of W_2^+ , and W_3^+ respectively. Using sputtered Cs, the analyte (M) can cluster together creating observable CsM⁺ ions [6–8], potentially providing a means to detect M⁺ or W⁺ in a quantitative manner. Using the CsM⁺ method, we can view CsW⁺ with high intensity signal. This serves as the control basis for future measurements. Table 2 displays possible peak identifications for the unshielded, irradiated W18 sample in the positive mode. Many transmutation products are observed throughout this collected spectra. Some representative observed transmutation products are Re⁺, Os⁺, ReO⁺, and OsO⁺ among others, in agreement with literature findings [9,10]. The CsM⁺ molecules, showing as CsW⁺, are observed among other products. Neutron bombardment has a major impact on the composition of the SIMS spectra for the irradiated SCW. We highlight ions, such as Hf, Ta, Re, and Os, due to the importance in the transmutation of W. Although ¹⁸¹W was



Fig. 2. Static ToF-SIMS spectral plot of the unshielded irradiated single crystal tungsten specimen, W18, in the m/z^+ range of 0–500 in the positive ion mode. Spectral results were reconstructed from scans 200 to 600.



Fig. 3. ToF-SIMS spectral plots of single crystal tungsten of different mass sections corresponding to W_1 , W_2 , and W_3 in the positive ion mode, with identified W isotopes.



Fig. 4. ToF-SIMS spectral plots of the unshielded, irradiated single crystal tungsten W18 specimen of different mass sections corresponding to W_1 , W_2 , and W_3 in the positive ion mode, with identified isotopes.

reported as a possible transmutation product of W post neutron irradiation in HFIR using atom probe tomography, [11] the identification of this peak is not unambiguous due to low ion count and poor mass deviation. Supplementary Table S1–S2 show ToF-SIMS acquisition conditions used for the pristine and irradiated SCW specimens, respectively.

3. Experimental Design, materials and methods

The W18 sample was irradiated at a temperature of 700 °C. The neutron fluence was consistently maintained at a level of 2.2–3.5x10²⁵ n/m² (equivalent to 0.6–0.7 dpa). All samples have a purity exceeding 99.99 wt% in W prior to irradiation. W18 was prepared by using the FIB to lift out a small specimen from the irradiated sample in a SEM. Two liftout samples were prepared, both were in tens of micrometers, i.e., 20 μ m \times 10 μ m. One of them was Pt welded onto a clean silicon (Si) wafer and the other to a TEM grid placed on a Si wafer. Depth profiling was performed on the liftout samples in the positive and negative mode consecutively. The positive data are reported here as isotopes of W are better detected in the positive ion mode.

ToF-SIMS depth profile spectra were obtained using an IONTOF TOF-SIMS V equipped with a 30 keV Bi3 metal ion gun. The analysis area was approximately 100–150 μ m² for the irradiated W18 liftout, and the FIB liftout was smaller than the analysis area. The electron flood gun was used to minimize surface charging for each sample. The figures shown here have identifications of molecules matching software (IONTOF SurfaceSpectra v7) suggested mass formula with a mass deviation of less than 65 ppm. The SIMS mass accuracy is defined as $\Delta M = 10^6 \times (m/z_{obs})$ $-m/z_{\text{the}})/m/z_{\text{the}}$ (expressed in ppm), where m/z_{obs} and m/z_{the} refer to the observed and theoretical mass to charge ratio of a specific peak in the negative or positive ion mode [12]. Depth profiling was performed using 1 keV and 2 keV Cs⁺ sputter beam for W18 and SCW samples, respectively. The sputtered areas were 500 \times 500 μ m² for the un-irradiated SCW and 400 \times 400 μ m² for the irradiated W18 liftout, respectively. The presented ToF-SIMS spectra herein were reconstructed from the depth profiling scans to reduce interferences of surface oxidation of W. A region of interest (ROI) was used to analyze the irradiated W18 sample as the actual tungsten liftout was small within the sputtered area nominally $100 \times 100 \ \mu\text{m}^2$ or $150 \times 150 \ \mu\text{m}^2$. Using the ROI results in lower ion counts. The analysis volume for each sample is $2.07 \times 10^4 \,\mu\text{m}^3$ and 9.20 \times 10³ µm³ for unirradiated SCW and irradiated W18, respectively, based on the correlative atomic force measurements of the crater depth and the assumption of anisotropic profiling.

Table 1

Peak identification of isotopes and clusters of the pristine single crystal tungsten in the positive ion mode from this work.

$m/z^+_{theo.}$	m/z $^+$ $_{obs.}$	ΔΜ,	Species	Assignment
		ppm		
179.9467	179.9473	3.3343	¹⁸⁰ W	Tungsten isotope 180
181.9477	181.9544	37.0608	$^{182}W^{+}$	Tungsten isotope 182
182.9497	182.9565	37.1677	$^{183}W^{+}$	Tungsten isotope 183
183.9504	183.9574	38.0991	W ⁺	Tungsten 184
185.9538	185.9610	38.8108	$^{186}W^{+}$	Tungsten isotope 186
314.8531	314.8447	26.7242	Cs ¹⁸² W ⁺	Tungsten isotope 182 and
315.8551	315.8468	26.2243	Cs $^{183}W^+$	Tungsten isotope 183 and
316.8558	316.8476	25.9889	CsW^+	Tungsten 184 and Cesium
318.8593	318.8508	26.4941	Cs $^{186}W^+$	Tungsten isotope 186 and Cesium cluster
363.8959	363.8973	4.0365	$^{182}W_{2}^{+}$	Tungsten isotope 182 cluster
364.8979	364.8992	3.5807	$^{183}W^{182}W^{+}$	Tungsten isotope 182 and 183 cluster
365.8999	365.8997	0.6241	$^{183}W_{2}^{+}$	Tungsten isotope 183 cluster
366.9006	366.9017	2.8730	$^{183}WW^{+}$	Tungsten isotope 182 and 184 cluster
367.9013	367.9033	5.3138	W_2^+	Tungsten 184 cluster
368.9040	368.9057	4.4236	$^{186}W^{183}W^{+}$	Tungsten isotope 186 and 183 cluster
369.9047	369.9064	4.3904	¹⁸⁶ WW ⁺	Tungsten isotope 186 and 184 cluster
371.9082	371.9096	3.7954	$^{186}W_{2}^{+}$	Tungsten isotope 186 cluster
496.8013	496.7850	32.9321	$Cs^{182}W_2^+$	Tungsten isotope 182 and Cesium cluster
497.8033	497.7794	48.0827	$Cs^{183}W^{182}W^+$	Tungsten isotope 183, 182andCesium cluster
498.8040	498.8046	1.0947	Cs ¹⁸² WW ⁺	Tungsten isotope 182, 184 and Cesium cluster
499.8061	499.7857	40.7977	Cs ¹⁸³ WW ⁺	Tungsten isotope 183, 184 and Cesium cluster
500.8068	500.8087	3.8080	CsW_2^+	Tungsten 184 and Cesium cluster
501.8095	501.8134	7.7065	$Cs^{186}W^{183}W^+$	Tungsten isotope 183, 186 and Cesium cluster
502.8102	502.8126	4.7647	Cs ¹⁸⁶ WW ⁺	Tungsten isotope 184, 186 and Cesium cluster
504.8136	504.8159	4.4924	$Cs^{186}W_2^+$	Tungsten isotope 186 and Cesium cluster
545.8441	545.8227	39.1855	$^{182}W_{3}^{+}$	Tungsten isotope 182 triplelet cluster
546.8461	546.8256	37.4082	$^{183}W^{182}W_2^+$	Tungsten isotope 182 and 183 cluster
547.8468	547.8259	38.1928	$W^{182}W^+_2$	Tungsten isotope 182 and 184 cluster
548.8488	548.8270	39.7093	$W^{183}W^{182}W^+$	Tungsten isotope 182, 183, and 184 cluster
549.8495	549.8284	38.3997	$W_2^{182}W^+$	Tungsten isotope 182 and 184 cluster
550.8515	550.8300	39.1138	$W_2^{183}W^+$	Tungsten isotope 183 and 184 cluster
551.8522	551.8313	38.0140	W_3^+	Tungsten isotope 184 cluster
552.8550	552.8323	41.0364	¹⁸⁶ W ¹⁸³ WW ⁺	Tungsten isotope 183. 184, and 186 cluster
553.8557	553.8342	38.7863	¹⁸⁶ WW ₂ ⁺	Tungsten isotope 184 and 186 cluster
554.8584	554.8348	42.4783	$^{186}W_{2}^{183}W^{+}$	Tungsten isotope 183 and 186 cluster
555.8591	555.8371	39.6194	¹⁸⁶ W ₂ W ⁺	Tungsten isotope 184 and 186 cluster
557.8625	557.8401	40.2012	$^{186}W_3^+$	Tungsten isotope 186 cluster

Footnotes

m/z + theoretical mass to charge ratio in the positive ion mode.

 m/z^+ obs.: observed mass to charge ratio in the positive ion mode.

 ΔM : $\Delta M = 10^6 \times (m/z^+_{obs.} - m/z^+_{theo.})/m/z^+_{theo.}$ (expressed in ppm) [12].

Table 2

Peak identification of isotopes and clusters of the unshielded, irradiated single crystal tungsten in the positive ion mode from this work.

$m/z^+_{theo.}$	m/z $^+$ $_{obs.}$	ΔM	Species	Assignment
179.9460	179.9459	0.4884	Hf^+	Hafnium 180
180.9474	180.9533	32.2815	Ta^+	Tantalum 181
181.9477	181.9464	7.0707	$^{182}W^{+}$	Tungsten isotope 182
182.9497	182.9480	9.2526	$^{183}W^{+}$	Tungsten isotope 183
183.9504	183.9478	14.2348	W^+	Tungsten 186
184.9524	184.9500	12.8795	¹⁸⁵ Re ⁺	Rhenium isotope 185
185.9538	185.9494	23.9162	$^{186}W^{+}$	Tungsten isotope 186
186.9552	186.9579	14.3986	Re ⁺	Rhenium 187
187.9553	187.9524	15.1571	¹⁸⁸ Os ⁺	Osmium isotope 188
188.9576	188.9608	17.0546	¹⁸⁹ Os ⁺	Osmium isotope 189
191.9609	191.9684	39.0661	Os^+	Osmium 192
365.8999	365.9224	61.5335	$^{183}W_{2}^{+}$	Tungsten isotope 183 cluster
366.9006	366.9218	57.6461	$W^{183}W^{+}$	Tungsten 184 and isotope 183
				cluster
368.9040	368.9165	33.7779	$^{186}W^{183}W^{+}$	Tungsten isotope 186 and 183
				cluster
369.9047	369.9275	61.5205	¹⁸⁶ WW ⁺	Tungsten isotope 186 and 184
				cluster
371.9082	371.9284	54.4100	$^{186}W_{2}^{+}$	Tungsten 186 cluster
373.9091	373.9272	48.3571	$Os^{182}W^{+}$	Osmium 192 and Tungsten
				182 cluster
375.9119	375.9298	47.8466	OsW^+	Osmium 192 and Tungsten
				184 cluster
377.9153	377.9228	19.9463	$Os^{186}W^+$	Osmium 192 and Tungsten
				isoptope 186 cluster
378.9167	378.9288	31.9680	ReOs ⁺	Rhenium 187 and Osmium
				192 cluster
381.9200	381.9313	29.7009	RePt ⁺	Rhenium 187 and Platinum
				195 cluster
382.9201	382.9246	11.6185	Re ¹⁹⁶ Pt ⁺	Rhenium isotope 195 and
				Platinum 195 cluster
383.9230	383.9309	20.6694	Ir ¹⁹¹ Ir ⁺	Irridium isotope 191and 193
				cluster
385.9253	385.9315	16.0416	Ir_2^+	Irridium 193 cluster

Footnotes.

m/z ⁺ _{theo.}: theoretical mass to charge ratio in the positive ion mode.

 m/z^+ obs.: observed mass to charge ratio in the positive ion mode.

 ΔM : $\Delta M = 10^6 \times (m/z^+_{obs.} - m/z^+_{theo.})/m/z^+_{theo.}$ (expressed in ppm) [12].

The peak identification procedure followed a multi-step process. The mass matching function calculates different combinations of periodic table elements to mass match a selected peak and it provides a mass deviation and match score. These combinations range from organics to inorganics. Using the "peak search" function within *SurfaceSpectra*, with parameters of SNR 3.0, max background 0.8, and minimum counts 25, a peak list was generated giving the best mass matching formula for the given m/z value under each specific sample. Isotopic ratios for each of the assigned peaks was considered before assignment. Peak assignment was further verified by literature search pertaining to these molecules.

SIMS spectral plotting was done using OriginPro 2023, where the data was extracted from the calibrated SIMS files and converted to ASCII files with bin equal to 1 to show raw data. Data files are made accessible to the public. Calibration points for each of the samples were selected to be the same. Calibration peaks include Na^+ , K^+ , W^+ , CsW^+ and W_2^+ in the positive ion mode. In addition to mass accuracy, the peak identification of SCW was compared with known ratios of isotopes of W in natural abundance and a good agreement was reached. Other isotopes of the transmutation products, such as Re and Os, are compared with known isotope theoretical values during peak assignment.

The transmutation reaction initiated during the fusion neutron irradiation cause formation of transmutation elements, such as Re, Os, and Ta, in the W-based PFMs. We report the first SIMS spectral detection of elements and isotopes related to SCW, including Hf, Ta, W, Re, and Os due to the importance in the transmutation of W as a PFM candidate in fusion applications [13]. Such SIMS mass spectral data are valuable as references of pure W without neutron irradiation. Additionally, these spectral results are useful to study the neutron irradiation effect on W,

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particularly in the identification of transmutation products with decent mass resolution and accuracy using SIMS. Speciation information like this is important in understanding the transmutation effects on PFMs and other structural materials and the implications on the mechanical properties and integrity of fusion materials.

CRediT authorship contribution statement

Gabriel D. Parker: Writing – review & editing, Writing – original draft, Investigation, Formal analysis, Data curation. Tobias K. Misicko: Writing – review & editing, Writing – original draft, Investigation, Formal analysis. Tanguy Teriler: Writing – review & editing, Methodology, Data curation. Yang Xiao: Writing – review & editing. Xiao-Ying Yu: Writing – review & editing, Writing – original draft, Validation, Supervision, Software, Resources, Project administration, Methodology, Investigation, Funding acquisition, Formal analysis, Data curation, Conceptualization.

Ethics Statement

The authors confirm that they have read and followed the ethical requirements for publication in Data in Brief and confirm that the current work does not involve human subjects, animal experiments, or any data collected from social media platforms.

Declaration of competing interest

The authors declare that they have no known competing financial interests or personal relationships that could have appeared to influence the work reported in this paper.

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Appendix A. Supplementary data

Supplementary data to this article can be found online at https://doi.org/10.1016/j.rsurfi.2025.100577.

Data availability

Data will be made available on request. Also available in github, https://github.com/Gparke4/Data-ToF-SIMS-spectral-analysis-ofpristine-and-neutron-irradiated-single-crystal-tungsten

Tungsten Data (Original data) (IEEE Data Portal)

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